

Notice of References Cited	Application/Control No. 10/594,846		Applicant(s)/Patent Under Reexamination IWAI ET AL.	
	Examiner G. NAGESH RAO		Art Unit 1792	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0078881 A1	06-2002	Cuomo et al.	117/84
*	B	US-2002/0086534 A1	07-2002	Cuomo et al.	438/689
*	C	US-2002/0175338 A1	11-2002	Sarayama et al.	257/95
*	D	US-2004/0134413 A1	07-2004	Iwata et al.	117/002
*	E	US-6,780,239 B2	08-2004	Sarayama et al.	117/36
*	F	US-6,861,130 B2	03-2005	D'Evelyn et al.	428/220
*	G	US-6,949,140 B2	09-2005	Sarayama et al.	117/81
*	H	US-2006/0037529 A1	02-2006	D'Evelyn et al.	117/036
*	I	US-7,001,457 B2	02-2006	Sarayama et al.	117/74
*	J	US-2006/0051942 A1	03-2006	Sasaki et al.	438/483
*	K	US-2006/0096521 A1	05-2006	D'Evelyn et al.	117/002
*	L	US-7,220,311 B2	05-2007	Iwata et al.	117/73
*	M	US-2007/0194408 A1	08-2007	Iwata et al.	257/613

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/594,846		Applicant(s)/Patent Under Reexamination IWAI ET AL.	
	Examiner G. NAGESH RAO		Art Unit 1792	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,261,775 B2	08-2007	Iwata et al.	117/81
*	B	US-2007/0209575 A1	09-2007	Iwai et al.	117/078
*	C	US-2007/0296061 A1	12-2007	Sasaki et al.	257/615
*	D	US-7,368,015 B2	05-2008	D'Evelyn et al.	117/224
*	E	US-7,449,064 B2	11-2008	Iwai et al.	117/81
*	F	US-2008/0302297 A1	12-2008	Ichimura et al.	117/73
*	G	US-2009/0000538 A1	01-2009	Iwai et al.	117/19
*	H	US-2009/0013924 A1	01-2009	Iwai et al.	117/64
*	I	US-7,531,038 B2	05-2009	Sarayama et al.	117/73
*	J	US-2009/0120354 A1	05-2009	Sarayama et al.	117/203
*	K	US-2009/0140287 A1	06-2009	Fujiwara et al.	257/103
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.